INFORMATION CITED BY APPLICANT(S) THAT MAY BE MATERIAL TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicant:

F.M. Schellenberg et al.

Attorney Docket No. MEGC122529

Application No.: -- 16-811418

Group Art Unit: -- 2825

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Title:

CREATING PHOTOLITHOGRAPHIC MASKS

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*Examiner				
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*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

RCT:pt